

# EUROPEAN PATENT OFFICE

## Patent Abstracts of Japan

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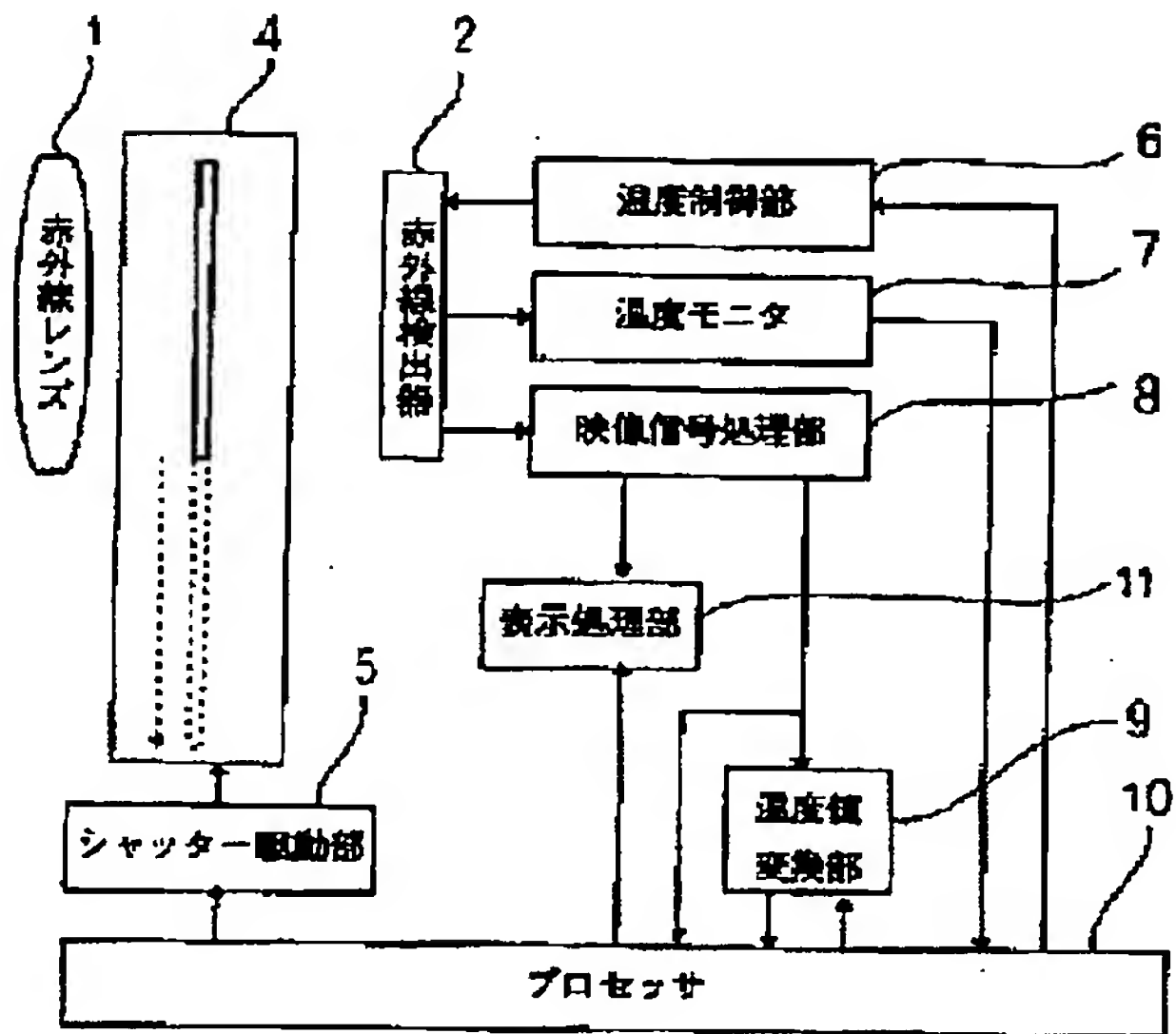
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APPLICANT : MITSUBISHI ELECTRIC CORP;

INVENTOR : YAMAGISHI AKIRA;

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TITLE : INFRARED TEMPERATURE  
MEASURING APPARATUS



**ABSTRACT :** PROBLEM TO BE SOLVED: To make an infrared detector usable as a calibration reference heat source for the temp. measurement by providing a means for controlling the temp. for constant temp. and a means for opening/closing a mirror-surface finished shutter and picking up the reflected image of the infrared detector.

**SOLUTION:** By having a shutter 4 slide along a plane at right angles to the incident optical axis of an infrared ray radiated by an object to be measured, the shutter is opened/closed. When the shutter 4 is closed, an infrared detector 2 picks up the image of the detector 2 itself which is reflected on the shutter 4. A correcting means for obtaining a correct temp. value accurately controls the temp. of the detector 2 for a constant temp., instead of a reference heat source 3. Thus, without using an exclusive reference heat source, the temp. can be measured similar to the conventional apparatus. Although the shutter 4 is shown with one sheet, but a plurality of shutters may be used. Thus the apparatus can be downsized and a more accurate temp. measurement can be made by working the shutter 4 into a recessed shape.

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